

December 1992

CMOS 4-Bit Magnitude Comparator

Features

- High Voltage Type (20V Rating)
- Expansion to 8, 12, 16 . . .4N Bits by Cascading Units
- Medium Speed Operation
 - Compares Two 4-Bit Words in 180ns (Typ.) at 10V
- 100% Tested for Quiescent Current at 20V
- Standardized Symmetrical Output Characteristics
- 5V, 10V and 15V Parametric Ratings
- Maximum Input Current of 1 μ A at 18V Over Full Package Temperature Range; 100nA at 18V and +25°C
- Noise Margin (Over Full Package/Temperature Range)
 - 1V at VDD = 5V
 - 2V at VDD = 10V
 - 2.5V at VDD = 15V
- Meets All Requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications

- Servo Motor Controls
- Process Controllers

Description

CD4585BMS is a 4-bit magnitude comparator designed for use in computer and logic applications that require the comparison of two 4-bit words. This logic circuit determines whether one 4-bit word (Binary or BCD) is "less than", "equal to" or "greater than" a second 4-bit word.

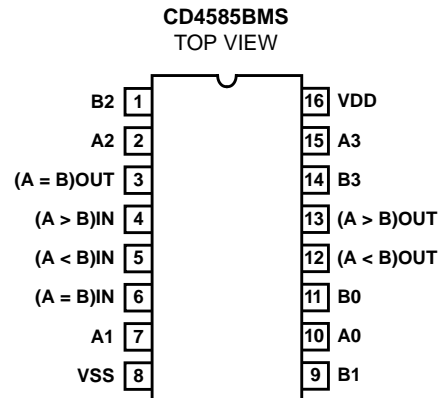
The CD4585BMS has eight comparing inputs (A3, B3, through A0, B0), three outputs (A < B, = B, A > B) and three cascading inputs (A < B, A = B, A > B) that permit system designers to expand the comparator function to 8, 12, 164N bits. When a single CD4585BMS is used, the cascading inputs are connected as follows: (A < B) = low, (A = B) = high, (A > B) = high.

Cascading thses units for comparision of more than 4 bits is accomplished as shown in Figure 9.

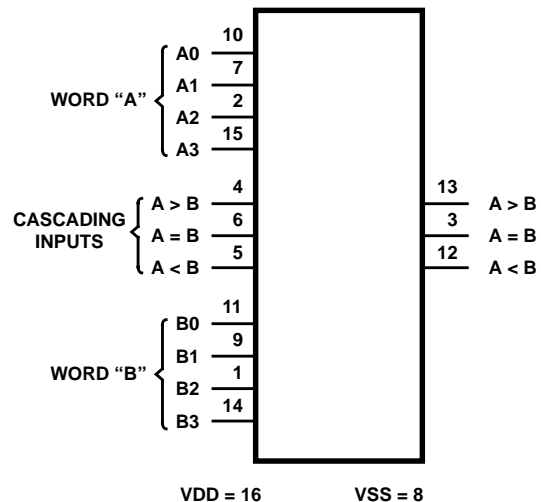
The CD4585BMS is supplied in these 16-lead outline packages:

| | |
|------------------|-----|
| Braze Seal DIP | H4T |
| Frit Seal DIP | H1E |
| Ceramic Flatpack | H6W |

Pinout



Functional Diagram



Specifications CD4585BMS

Absolute Maximum Ratings

| | |
|---|---|
| DC Supply Voltage Range, (VDD) | -0.5V to +20V (Voltage Referenced to VSS Terminals) |
| Input Voltage Range, All Inputs | -0.5V to VDD +0.5V |
| DC Input Current, Any One Input | ±10mA |
| Operating Temperature Range | -55°C to +125°C Package Types D, F, K, H |
| Storage Temperature Range (TSTG) | -65°C to +150°C |
| Lead Temperature (During Soldering) | +265°C At Distance 1/16 ± 1/32 Inch (1.59mm ± 0.79mm) from case for 10s Maximum |

Reliability Information

| | | |
|---|---|---------------|
| Thermal Resistance | θ_{ja} | θ_{jc} |
| Ceramic DIP and FRIT Package | 80°C/W | 20°C/W |
| Flatpack Package | 70°C/W | 20°C/W |
| Maximum Package Power Dissipation (PD) at +125°C | | |
| For $T_A = -55^\circ\text{C}$ to $+100^\circ\text{C}$ (Package Type D, F, K) | 500mW | |
| For $T_A = +100^\circ\text{C}$ to $+125^\circ\text{C}$ (Package Type D, F, K) | Derate Linearity at 12mW/°C to 200mW | |
| Device Dissipation per Output Transistor | 100mW | |
| For $T_A =$ Full Package Temperature Range (All Package Types) | | |
| Junction Temperature | +175°C | |

TABLE 1. DC ELECTRICAL PERFORMANCE CHARACTERISTICS

| PARAMETER | SYMBOL | CONDITIONS (NOTE 1) | | GROUP A SUBGROUPS | TEMPERATURE | LIMITS | | UNITS |
|-----------------------------|--------|---------------------------------------|-----------|----------------------|----------------------|----------------|----------------|-------|
| | | | | | | MIN | MAX | |
| Supply Current | IDD | VDD = 20V, VIN = VDD or GND | | 1 | +25°C | - | 10 | μA |
| | | | | 2 | +125°C | - | 1000 | μA |
| | | VDD = 18V, VIN = VDD or GND | | 3 | -55°C | - | 10 | μA |
| Input Leakage Current | IIL | VIN = VDD or GND | VDD = 20 | 1 | +25°C | -100 | - | nA |
| | | | | 2 | +125°C | -1000 | - | nA |
| | | | VDD = 18V | 3 | -55°C | -100 | - | nA |
| Input Leakage Current | IIH | VIN = VDD or GND | VDD = 20 | 1 | +25°C | - | 100 | nA |
| | | | | 2 | +125°C | - | 1000 | nA |
| | | | VDD = 18V | 3 | -55°C | - | 100 | nA |
| Output Voltage | VOL15 | VDD = 15V, No Load | | 1, 2, 3 | +25°C, +125°C, -55°C | - | 50 | mV |
| Output Voltage | VOH15 | VDD = 15V, No Load (Note 3) | | 1, 2, 3 | +25°C, +125°C, -55°C | 14.95 | - | V |
| Output Current (Sink) | IOL5 | VDD = 5V, VOUT = 0.4V | | 1 | +25°C | 0.53 | - | mA |
| Output Current (Sink) | IOL10 | VDD = 10V, VOUT = 0.5V | | 1 | +25°C | 1.4 | - | mA |
| Output Current (Sink) | IOL15 | VDD = 15V, VOUT = 1.5V | | 1 | +25°C | 3.5 | - | mA |
| Output Current (Source) | IOH5A | VDD = 5V, VOUT = 4.6V | | 1 | +25°C | - | -0.53 | mA |
| Output Current (Source) | IOH5B | VDD = 5V, VOUT = 2.5V | | 1 | +25°C | - | -1.8 | mA |
| Output Current (Source) | IOH10 | VDD = 10V, VOUT = 9.5V | | 1 | +25°C | - | -1.4 | mA |
| Output Current (Source) | IOH15 | VDD = 15V, VOUT = 13.5V | | 1 | +25°C | - | -3.5 | mA |
| N Threshold Voltage | VNTH | VDD = 10V, ISS = -10μA | | 1 | +25°C | -2.8 | -0.7 | V |
| P Threshold Voltage | VPTH | VSS = 0V, IDD = 10μA | | 1 | +25°C | 0.7 | 2.8 | V |
| Functional | F | VDD = 2.8V, VIN = VDD or GND | | 7 | +25°C | VOH > VDD/2 | VOL < VDD/2 | V |
| | | VDD = 20V, VIN = VDD or GND | | 7 | +25°C | | | |
| | | VDD = 18V, VIN = VDD or GND | | 8A | +125°C | | | |
| | | VDD = 3V, VIN = VDD or GND | | 8B | -55°C | | | |
| Input Voltage Low (Note 2) | VIL | VDD = 5V, VOH > 4.5V, VOL < 0.5V | | 1, 2, 3 | +25°C, +125°C, -55°C | - | 1.5 | V |
| Input Voltage High (Note 2) | VIH | VDD = 5V, VOH > 4.5V, VOL < 0.5V | | 1, 2, 3 | +25°C, +125°C, -55°C | 3.5 | - | V |
| Input Voltage Low (Note 2) | VIL | VDD = 15V, VOH > 13.5V, VOL < 1.5V | | 1, 2, 3 | +25°C, +125°C, -55°C | - | 4 | V |
| Input Voltage High (Note 2) | VIH | VDD = 15V, VOH > 13.5V, VOL < 1.5V | | 1, 2, 3 | +25°C, +125°C, -55°C | 11 | - | V |

NOTES: 1. All voltages referenced to device GND, 100% testing being implemented. 3. For accuracy, voltage is measured differentially to VDD. Limit is 0.050V max.
2. Go/No Go test with limits applied to inputs.

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TABLE 2. AC ELECTRICAL PERFORMANCE CHARACTERISTICS

| PARAMETER | SYMBOL | CONDITIONS (NOTE 1, 2) | GROUP A SUBGROUPS | TEMPERATURE | LIMITS | | UNITS |
|---|----------------|----------------------------|----------------------|---------------|--------|-----|-------|
| | | | | | MIN | MAX | |
| Propagation Delay Comparing Inputs to Outputs | TPHL1 TPLH1 | VDD = 5V, VIN = VDD or GND | 9 | +25°C | - | 600 | ns |
| | | | 10, 11 | +125°C, -55°C | - | 810 | ns |
| Propagation Delay Cascading Inputs to Out- puts | TPHL2 TPLH2 | VDD = 5V, VIN = VDD or GND | 9 | +25°C | - | 400 | ns |
| | | | 10, 11 | +125°C, -55°C | - | 540 | ns |
| Transition Time | TTHL TTLH | VDD = 5V, VIN = VDD or GND | 9 | +25°C | - | 200 | ns |
| | | | 10, 11 | +125°C, -55°C | - | 270 | ns |

NOTES:

1. CL = 50pF, RL = 200K, Input TR, TF < 20ns.
2. -55°C and +125°C limits guaranteed, 100% testing being implemented.

TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS

| PARAMETER | SYMBOL | CONDITIONS | NOTES | TEMPERATURE | LIMITS | | UNITS |
|-------------------------|--------|-------------------------------|-------|-------------------------|--------|-------|-------|
| | | | | | MIN | MAX | |
| Supply Current | IDD | VDD = 5V, VIN = VDD or GND | 1, 2 | -55°C, +25°C | - | 5 | μA |
| | | | | +125°C | - | 150 | μA |
| | | VDD = 10V, VIN = VDD or GND | 1, 2 | -55°C, +25°C | - | 10 | μA |
| | | | | +125°C | - | 300 | μA |
| | | VDD = 15V, VIN = VDD or GND | 1, 2 | -55°C, +25°C | - | 10 | μA |
| | | | | +125°C | - | 600 | μA |
| Output Voltage | VOL | VDD = 5V, No Load | 1, 2 | +25°C, +125°C, -55°C | - | 50 | mV |
| Output Voltage | VOL | VDD = 10V, No Load | 1, 2 | +25°C, +125°C, -55°C | - | 50 | mV |
| Output Voltage | VOH | VDD = 5V, No Load | 1, 2 | +25°C, +125°C, -55°C | 4.95 | - | V |
| Output Voltage | VOH | VDD = 10V, No Load | 1, 2 | +25°C, +125°C, -55°C | 9.95 | - | V |
| Output Current (Sink) | IOL5 | VDD = 5V, VOUT = 0.4V | 1, 2 | +125°C | 0.36 | - | mA |
| | | | | -55°C | 0.64 | - | mA |
| Output Current (Sink) | IOL10 | VDD = 10V, VOUT = 0.5V | 1, 2 | +125°C | 0.9 | - | mA |
| | | | | -55°C | 1.6 | - | mA |
| Output Current (Sink) | IOL15 | VDD = 15V, VOUT = 1.5V | 1, 2 | +125°C | 2.4 | - | mA |
| | | | | -55°C | 4.2 | - | mA |
| Output Current (Source) | IOH5A | VDD = 5V, VOUT = 4.6V | 1, 2 | +125°C | - | -0.36 | mA |
| | | | | -55°C | - | -0.64 | mA |
| Output Current (Source) | IOH5B | VDD = 5V, VOUT = 2.5V | 1, 2 | +125°C | - | -1.15 | mA |
| | | | | -55°C | - | -2.0 | mA |
| Output Current (Source) | IOH10 | VDD = 10V, VOUT = 9.5V | 1, 2 | +125°C | - | -0.9 | mA |
| | | | | -55°C | - | -1.6 | mA |
| Output Current (Source) | IOH15 | VDD = 15V, VOUT = 13.5V | 1, 2 | +125°C | - | -2.4 | mA |
| | | | | -55°C | - | -4.2 | mA |
| Input Voltage Low | VIL | VDD = 10V, VOH > 9V, VOL < 1V | 1, 2 | +25°C, +125°C, -55°C | - | 3 | V |
| Input Voltage High | VIH | VDD = 10V, VOH > 9V, VOL < 1V | 1, 2 | +25°C, +125°C, -55°C | +7 | - | V |

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TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS (Continued)

| PARAMETER | SYMBOL | CONDITIONS | NOTES | TEMPERATURE | LIMITS | | UNITS |
|---|----------------|------------|---------|-------------|--------|-----|-------|
| | | | | | MIN | MAX | |
| Propagation Delay Comparing Inputs to Outputs | TPHL1 TPLH1 | VDD = 10V | 1, 2, 3 | +25°C | - | 250 | ns |
| | | VDD = 15V | 1, 2, 3 | +25°C | - | 160 | ns |
| Propagation Delay Cascading Inputs to Out- puts | TPHL2 TPLH2 | VDD = 10V | 1, 2, 3 | +25°C | - | 160 | ns |
| | | VDD = 15V | 1, 2, 3 | +25°C | - | 120 | ns |
| Transition Time | TTHL TTLH | VDD = 10V | 1, 2, 3 | +25°C | - | 100 | ns |
| | | VDD = 15V | 1, 2, 3 | +25°C | - | 80 | ns |
| Input Capacitance | CIN | Any Inputs | 1, 2 | +25°C | - | 7.5 | pF |

NOTES:

1. All voltages referenced to device GND.
2. The parameters listed on Table 3 are controlled via design or process and are not directly tested. These parameters are characterized on initial design release and upon design changes which would affect these characteristics.
3. CL = 50pF, RL = 200K, Input TR, TF < 20ns.

TABLE 4. POST IRRADIATION ELECTRICAL PERFORMANCE CHARACTERISTICS

| PARAMETER | SYMBOL | CONDITIONS | NOTES | TEMPERATURE | LIMITS | | UNITS |
|------------------------------|--------------|-----------------------------|------------|-------------|----------------|--------------------------|-------|
| | | | | | MIN | MAX | |
| Supply Current | IDD | VDD = 20V, VIN = VDD or GND | 1, 4 | +25°C | - | 25 | μA |
| N Threshold Voltage | VNTH | VDD = 10V, ISS = -10μA | 1, 4 | +25°C | -2.8 | -0.2 | V |
| N Threshold Voltage Delta | ΔVTN | VDD = 10V, ISS = -10μA | 1, 4 | +25°C | - | ±1 | V |
| P Threshold Voltage | VTP | VSS = 0V, IDD = 10μA | 1, 4 | +25°C | 0.2 | 2.8 | V |
| P Threshold Voltage Delta | ΔVTP | VSS = 0V, IDD = 10μA | 1, 4 | +25°C | - | ±1 | V |
| Functional | F | VDD = 18V, VIN = VDD or GND | 1 | +25°C | VOH > VDD/2 | VOL < VDD/2 | V |
| | | VDD = 3V, VIN = VDD or GND | | | | | |
| Propagation Delay Time | TPHL TPLH | VDD = 5V | 1, 2, 3, 4 | +25°C | - | 1.35 x +25°C Limit | ns |

- NOTES: 1. All voltages referenced to device GND. 2. CL = 50pF, RL = 200K, Input TR, TF < 20ns. 3. See Table 2 for +25°C limit. 4. Read and Record

TABLE 5. BURN-IN AND LIFE TEST DELTA PARAMETERS +25°C

| PARAMETER | SYMBOL | DELTA LIMIT |
|-------------------------|--------|--------------------------|
| Supply Current - MSI-2 | IDD | ± 1.0μA |
| Output Current (Sink) | IOL5 | ± 20% x Pre-Test Reading |
| Output Current (Source) | IOH5A | ± 20% x Pre-Test Reading |

TABLE 6. APPLICABLE SUBGROUPS

| CONFORMANCE GROUP | MIL-STD-883 METHOD | GROUP A SUBGROUPS | READ AND RECORD |
|-------------------------------|-----------------------|-------------------|------------------|
| Initial Test (Pre Burn-In) | 100% 5004 | 1, 7, 9 | IDD, IOL5, IOH5A |
| Interim Test 1 (Post Burn-In) | 100% 5004 | 1, 7, 9 | IDD, IOL5, IOH5A |
| Interim Test 2 (Post Burn-In) | 100% 5004 | 1, 7, 9 | IDD, IOL5, IOH5A |
| PDA (Note 1) | 100% 5004 | 1, 7, 9, Deltas | |
| Interim Test 3 (Post Burn-In) | 100% 5004 | 1, 7, 9 | IDD, IOL5, IOH5A |

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TABLE 6. APPLICABLE SUBGROUPS (Continued)

| CONFORMANCE GROUP | | MIL-STD-883 METHOD | GROUP A SUBGROUPS | READ AND RECORD |
|-------------------|--------------|--------------------|---------------------------------------|------------------------------|
| PDA (Note 1) | | 100% 5004 | 1, 7, 9, Deltas | |
| Final Test | | 100% 5004 | 2, 3, 8A, 8B, 10, 11 | |
| Group A | | Sample 5005 | 1, 2, 3, 7, 8A, 8B, 9, 10, 11 | |
| Group B | Subgroup B-5 | Sample 5005 | 1, 2, 3, 7, 8A, 8B, 9, 10, 11, Deltas | Subgroups 1, 2, 3, 9, 10, 11 |
| | Subgroup B-6 | Sample 5005 | 1, 7, 9 | |
| Group D | | Sample 5005 | 1, 2, 3, 8A, 8B, 9 | Subgroups 1, 2 3 |

NOTE: 1. 5% Parametric, 3% Functional; Cumulative for Static 1 and 2.

TABLE 7. TOTAL DOSE IRRADIATION

| CONFORMANCE GROUPS | MIL-STD-883 METHOD | TEST | | READ AND RECORD | |
|--------------------|--------------------|-----------|------------|-----------------|------------|
| | | PRE-IRRAD | POST-IRRAD | PRE-IRRAD | POST-IRRAD |
| Group E Subgroup 2 | 5005 | 1, 7, 9 | Table 4 | 1, 9 | Table 4 |

TABLE 8. BURN-IN AND IRRADIATION TEST CONNECTIONS

| FUNCTION | OPEN | GROUND | VDD | 9V ± -0.5V | OSCILLATOR | |
|----------------------------|-----------|----------------------|---------------------------------|------------|------------|-------|
| | | | | | 50kHz | 25kHz |
| Static Burn-In 1 Note 1 | 3, 12, 13 | 1, 2, 4 - 11, 14, 15 | 16 | | | |
| Static Burn-In 2 Note 1 | 3, 12, 13 | 8 | 1, 2, 4 - 7, 9 - 11, 14 - 16 | | | |
| Dynamic Burn-In Note 1 | - | 5 - 9, 11, 14, 15 | 1, 4, 16 | 3, 12, 13 | 2 | 10 |
| Irradiation Note 2 | 3, 12, 13 | 8 | 1, 2, 4 - 7, 9 - 11, 14 - 16 | | | |

NOTE:

- Each pin except VDD and GND will have a series resistor of $10K \pm 5\%$, $VDD = 18V \pm 0.5V$
- Each pin except VDD and GND will have a series resistor of $47K \pm 5\%$; Group E, Subgroup 2, sample size is 4 dice/wafer, 0 failures, $VDD = 10V \pm 0.5V$

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CD4585BMS

Logic Diagram

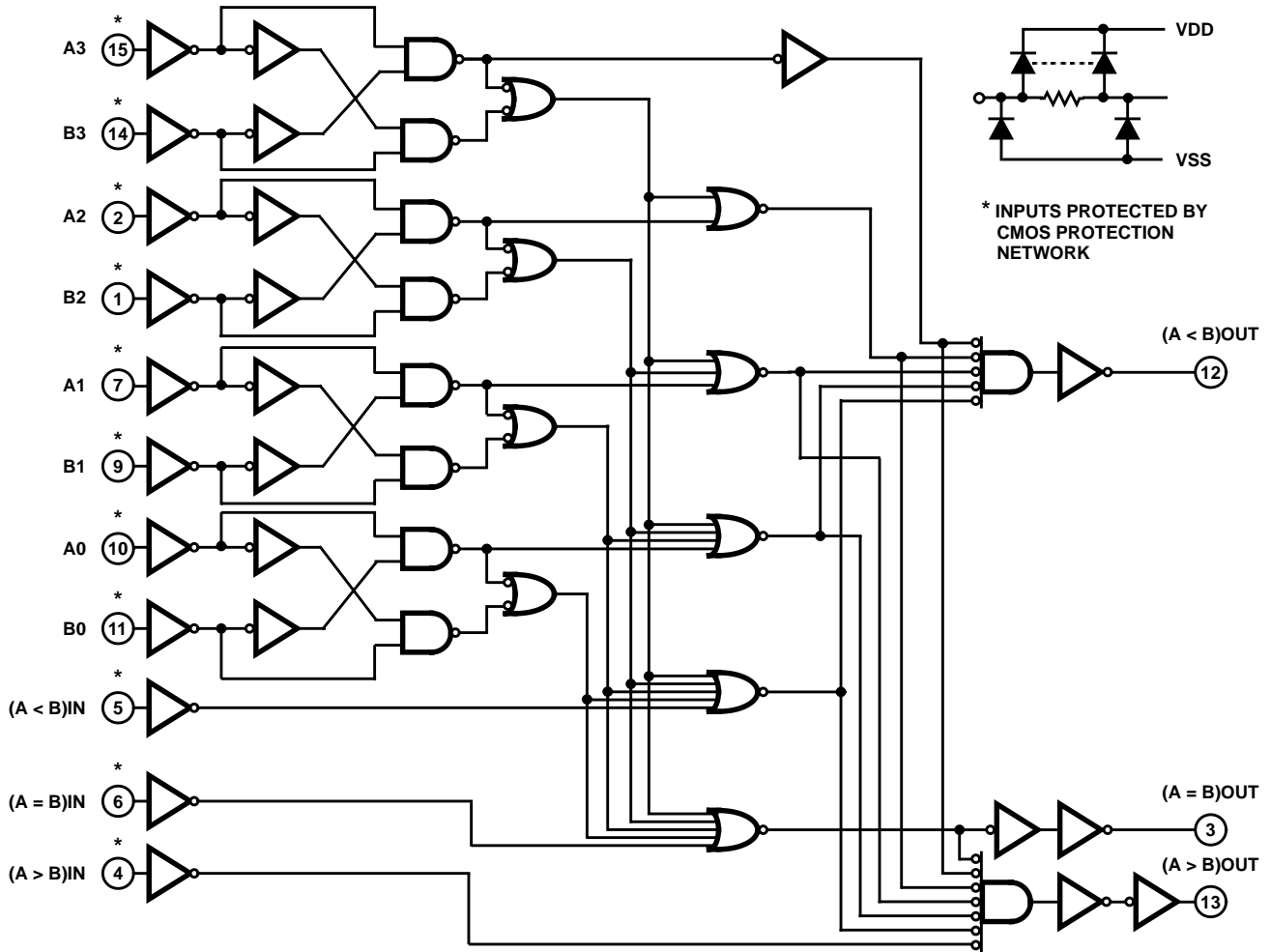


FIGURE 1. LOGIC DIAGRAM

TRUTH TABLE

| INPUTS | | | | | | | OUTPUTS | | |
|-----------|---------|---------|---------|-----------|-------|-------|---------|-------|-------|
| COMPARING | | | | CASCADING | | | | | |
| A3, B3 | A2, B2 | A1, B1 | A0, B0 | A < B | A = B | A > B | A < B | A = B | A > B |
| A3 > B3 | X | X | X | X | X | 1 | 0 | 0 | 1 |
| A3 = B3 | A2 > B2 | X | X | X | X | 1 | 0 | 0 | 1 |
| A3 = B3 | A2 = B2 | A1 > B1 | X | X | X | 1 | 0 | 0 | 1 |
| A3 = B3 | A2 = B2 | A1 = B1 | A0 > B0 | X | X | 1 | 0 | 0 | 1 |
| A3 = B3 | A2 = B2 | A1 = B1 | A0 = B0 | 0 | 0 | 1 | 0 | 0 | 1 |
| A3 = B3 | A2 = B2 | A1 = B1 | A0 = B0 | 0 | 1 | X | 0 | 1 | 0 |
| A3 = B3 | A2 = B2 | A1 = B1 | A0 = B0 | 1 | 0 | X | 1 | 0 | 0 |
| A3 = B3 | A2 = B2 | A1 = B1 | A0 < B0 | X | X | X | 1 | 0 | 0 |
| A3 = B3 | A2 = B2 | A1 < B1 | X | X | X | X | 1 | 0 | 0 |
| A3 = B3 | A2 < B2 | X | X | X | X | X | 1 | 0 | 0 |
| A3 < B3 | X | X | X | X | X | X | 1 | 0 | 0 |

X = Don't Care

Logic 1 = High Level

Logic 0 = Low Level

Typical Performance Characteristics

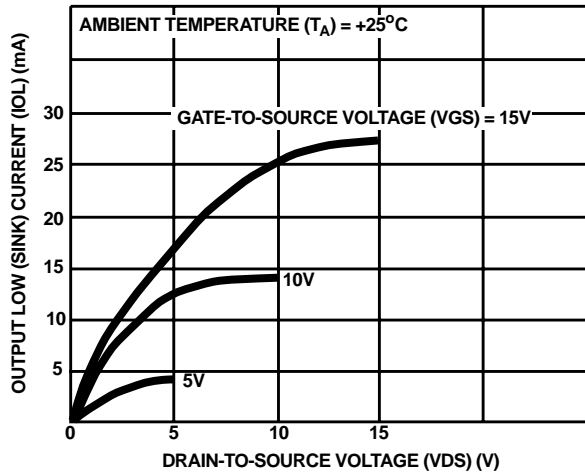


FIGURE 2. TYPICAL OUTPUT LOW (SINK) CURRENT CHARACTERISTICS

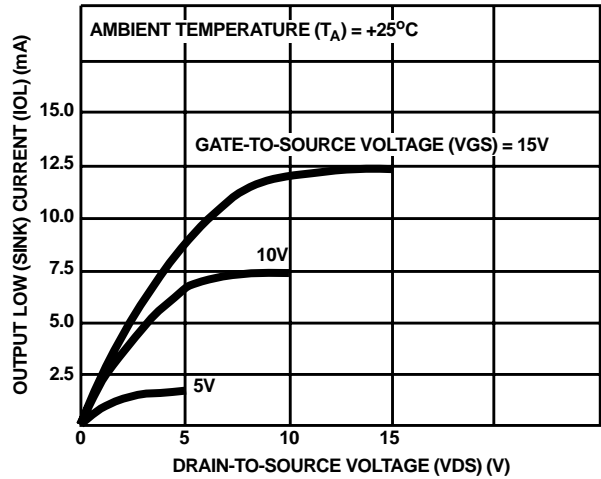


FIGURE 3. MINIMUM OUTPUT LOW (SINK) CURRENT CHARACTERISTICS

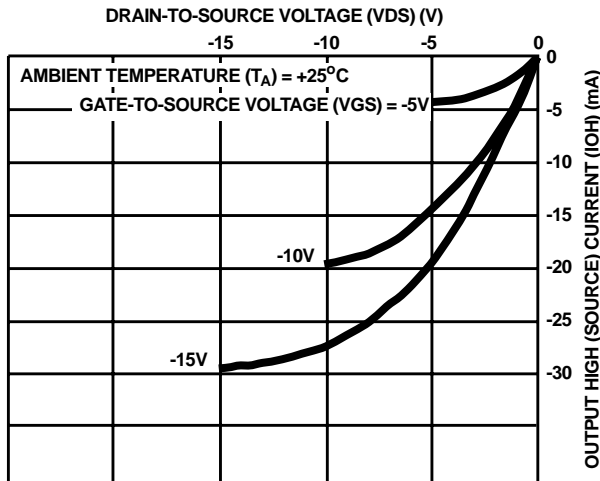


FIGURE 4. TYPICAL OUTPUT HIGH (SOURCE) CURRENT CHARACTERISTICS

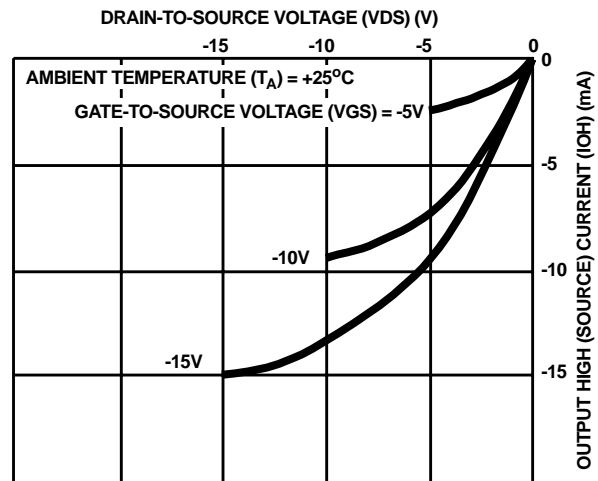


FIGURE 5. MINIMUM OUTPUT HIGH (SOURCE) CURRENT CHARACTERISTICS

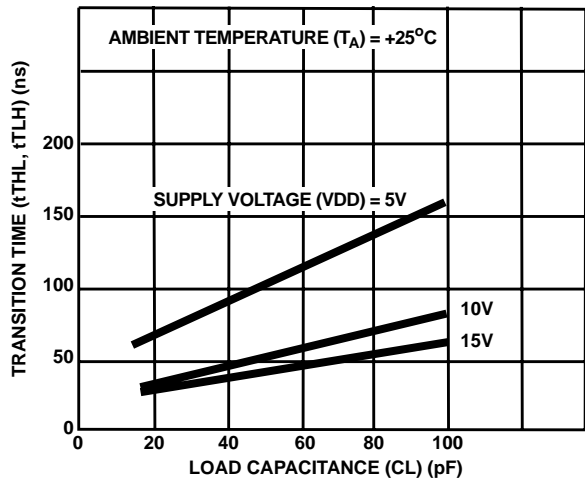


FIGURE 6. TYPICAL TRANSITION TIME AS A FUNCTION OF LOAD CAPACITANCE

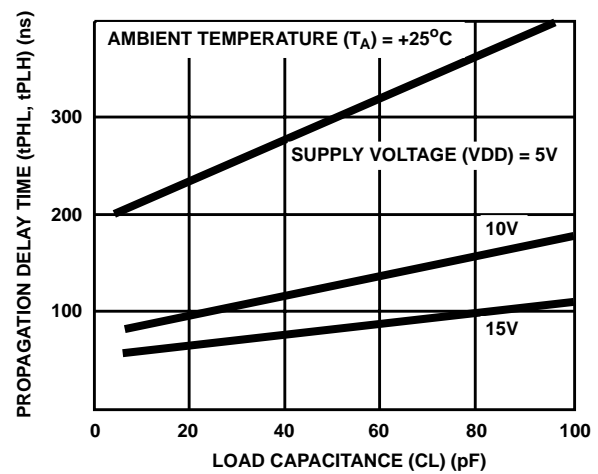


FIGURE 7. TYPICAL PROPAGATION DELAY TIME ("COMPARING INPUTS" TO OUTPUTS) AS A FUNCTION OF LOAD CAPACITANCE

CD4585BMS

Typical Performance Characteristics (Continued)

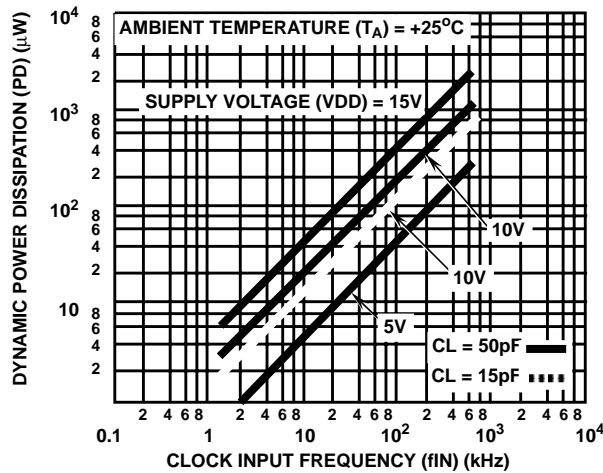


FIGURE 8. TYPICAL DYNAMIC POWER DISSIPATION AS A FUNCTION OF CLOCK INPUT FREQUENCY

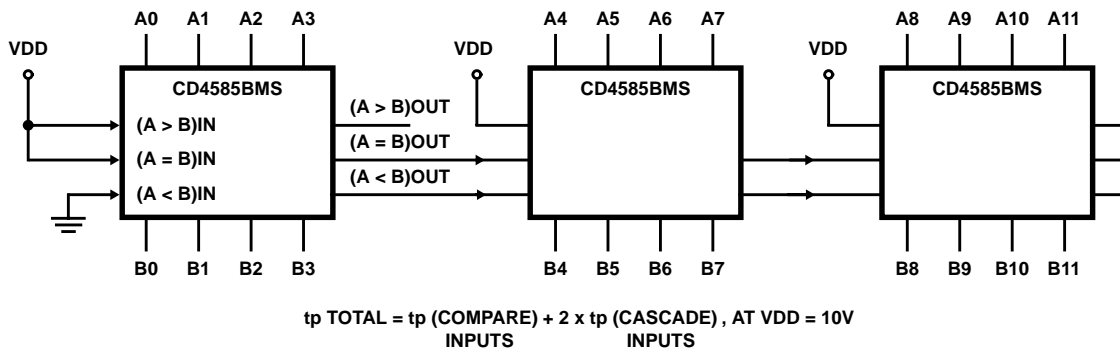
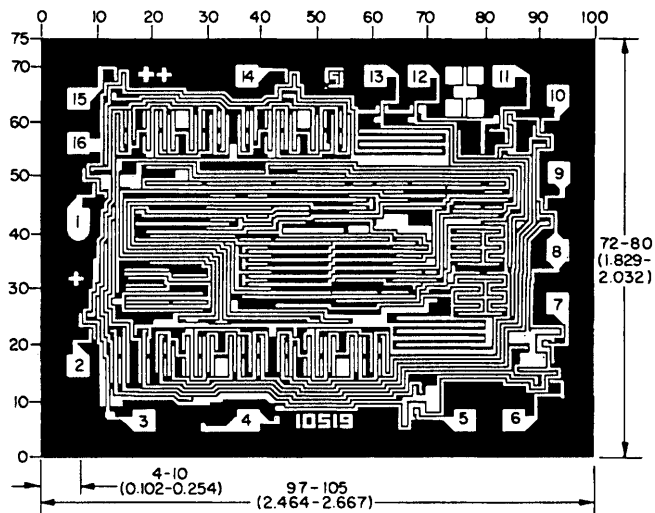


FIGURE 9. TYPICAL SPEED CHARACTERISTICS OF A 12-BIT COMPARATOR

Chip Dimensions and Pad Layout



Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

- METALLIZATION:** Thickness: $11\text{k}\text{\AA} - 14\text{k}\text{\AA}$, AL.
- PASSIVATION:** $10.4\text{k}\text{\AA} - 15.6\text{k}\text{\AA}$, Silane
- BOND PADS:** 0.004 inches X 0.004 inches MIN
- DIE THICKNESS:** 0.0198 inches - 0.0218 inches